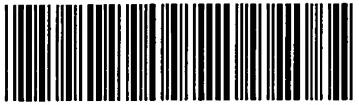


<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/827,313	YAMAOKA ET AL.	
				Examiner	Art Unit	
				Hai H. Huynh	3747	

<b>SEARCHED</b>			
Class	Subclass	Date	Examiner
123	90.11	7/13/2005	HHH
123	90.15	7/13/2005	HHH
123	305	7/13/2005	HHH
123	318	7/13/2005	HHH
123	406.11	7/13/2005	HHH
123	406.45	7/13/2005	HHH
123	406.48	7/13/2005	HHH
123	435	7/13/2005	HHH
123	672	7/13/2005	HHH
123	568.11	7/13/2005	HHH
123	568.14	7/13/2005	HHH
123	299	7/13/2005	HHH
123	399	7/13/2005	HHH
update	search	3/22/2006	HHH

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
above	search	3/22/2006	HHH

<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
	DATE	EXMR
East	7/13/2005	HHH
	3/22/2006	HHH